

APPROVED
BY
DRAFTSMAN

O.G. FIG. 5	CLASS 0148	SUBCLASS 23-116
714	724	

6185707

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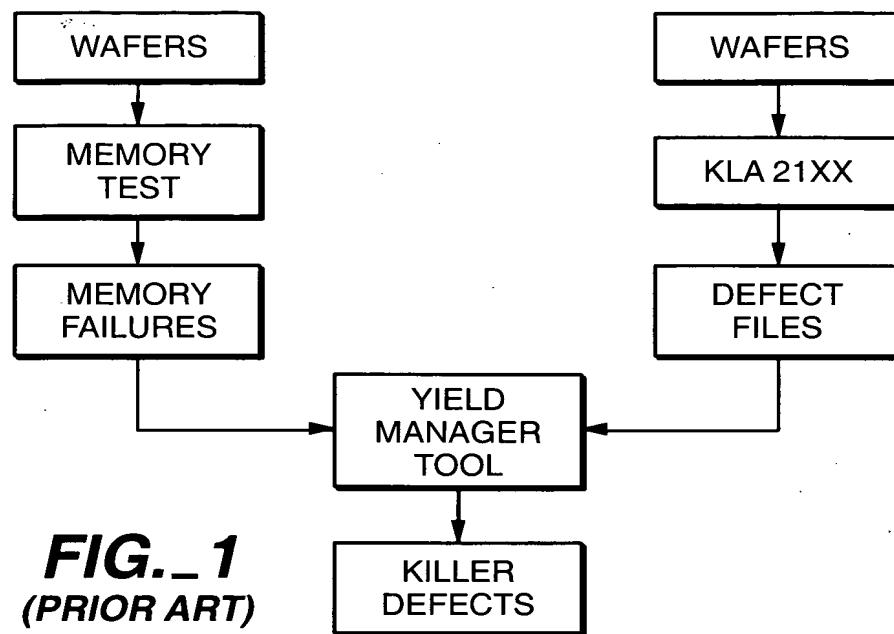


FIG._ 1
(PRIOR ART)

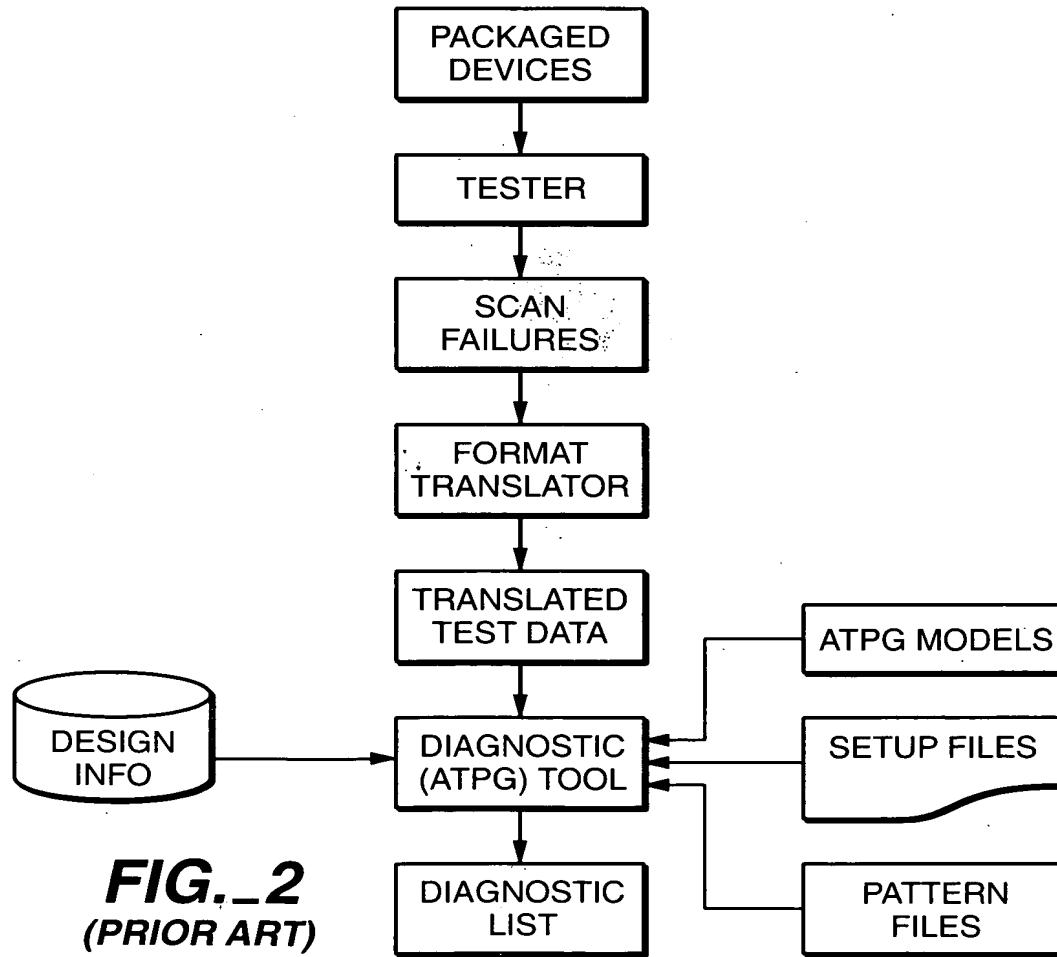


FIG._ 2
(PRIOR ART)

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APPROVED	O.G. FIG.	
BY	QA28	SUBCLASS
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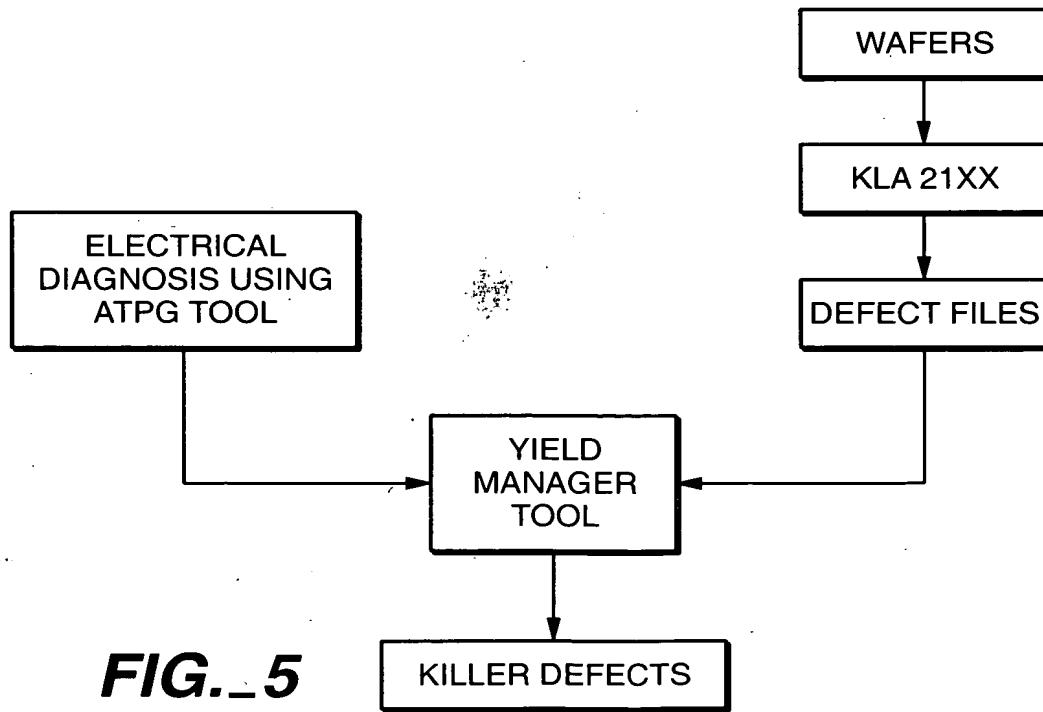
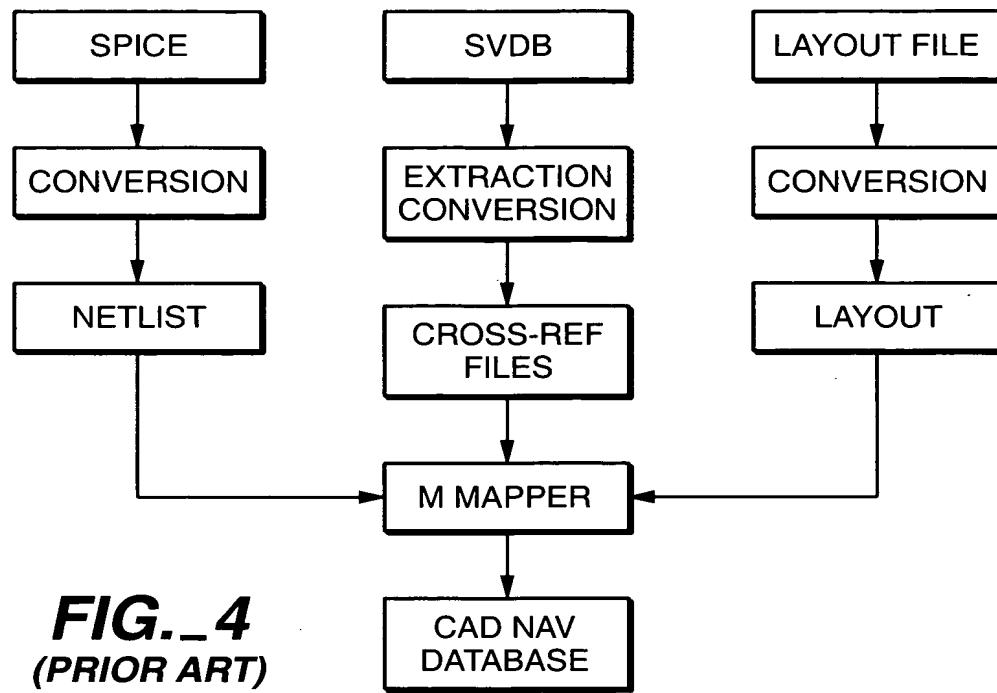
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```

DeviceID = DEMOID
LotID = TESTLOT01
WaferID = 01
DIE = -4,0
datalog.scan.10 diagnosis summary, #failing_patterns=9  #defects=2
#unexplained_fails=2
unexplained patterns = 212 250
-----
fault candidates for defect 1, #failing_patterns_explained=5
-----
Warning: Fault candidates will cause passing patterns to fail.
failing patterns explained = 322 706 738 770
type  code  pin_pathname
-----
1  DS  /XTIO_0/XTTLI8_1612/N2_23
1  DS  /PI9
-----
diagnosis CPU time = .68 sec

```

FIG.-3
(PRIOR ART)



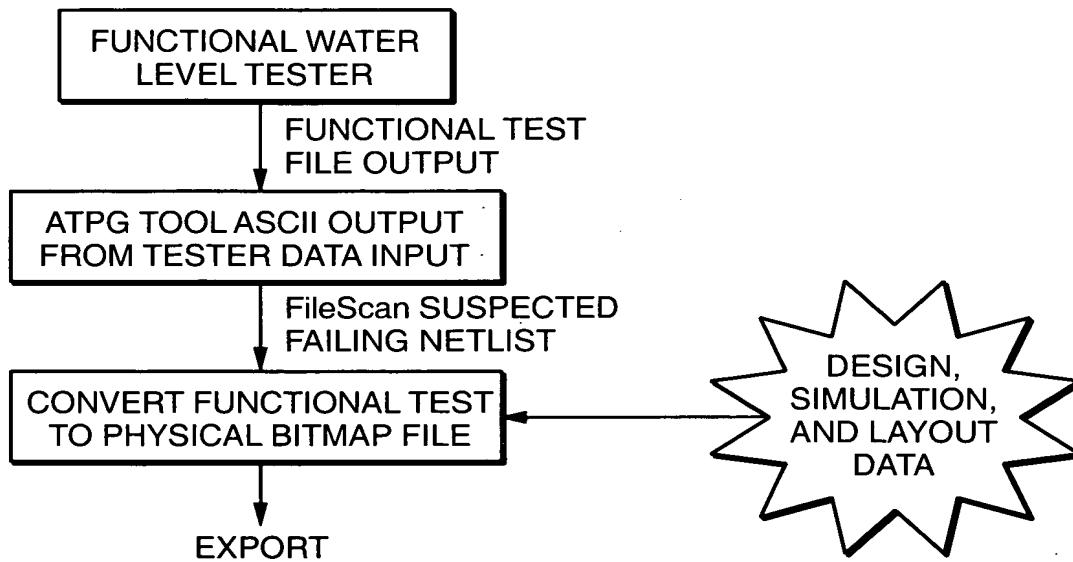
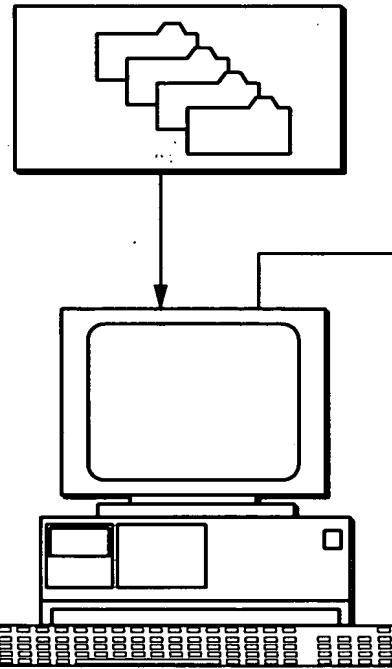


FIG._6

TESTER GENERATED FILES
TESTERS GENERATE
DATALOGS FOR EACH
DIE TESTED.



FastScan UNIX SERVER
A FRACTION OF THE
DATALOGS ARE TRANSLATED
INTO FastScan FORMAT.

DESIGN DATA
LogicMap READS THE
GDSII FILE INPUT,
NETLIST AND LSV DATA.

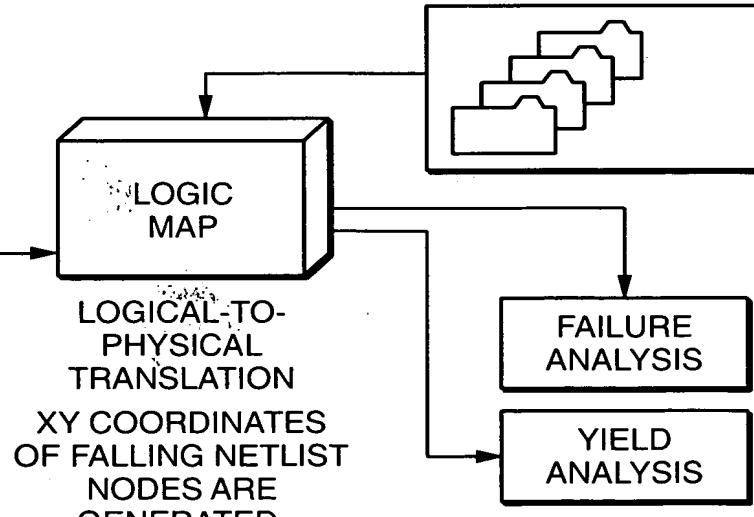


FIG._10

APPROVED BY	O.G. FIG.
DRAFTSMAN	CLASS 148 SUBCLASS 254 714 724

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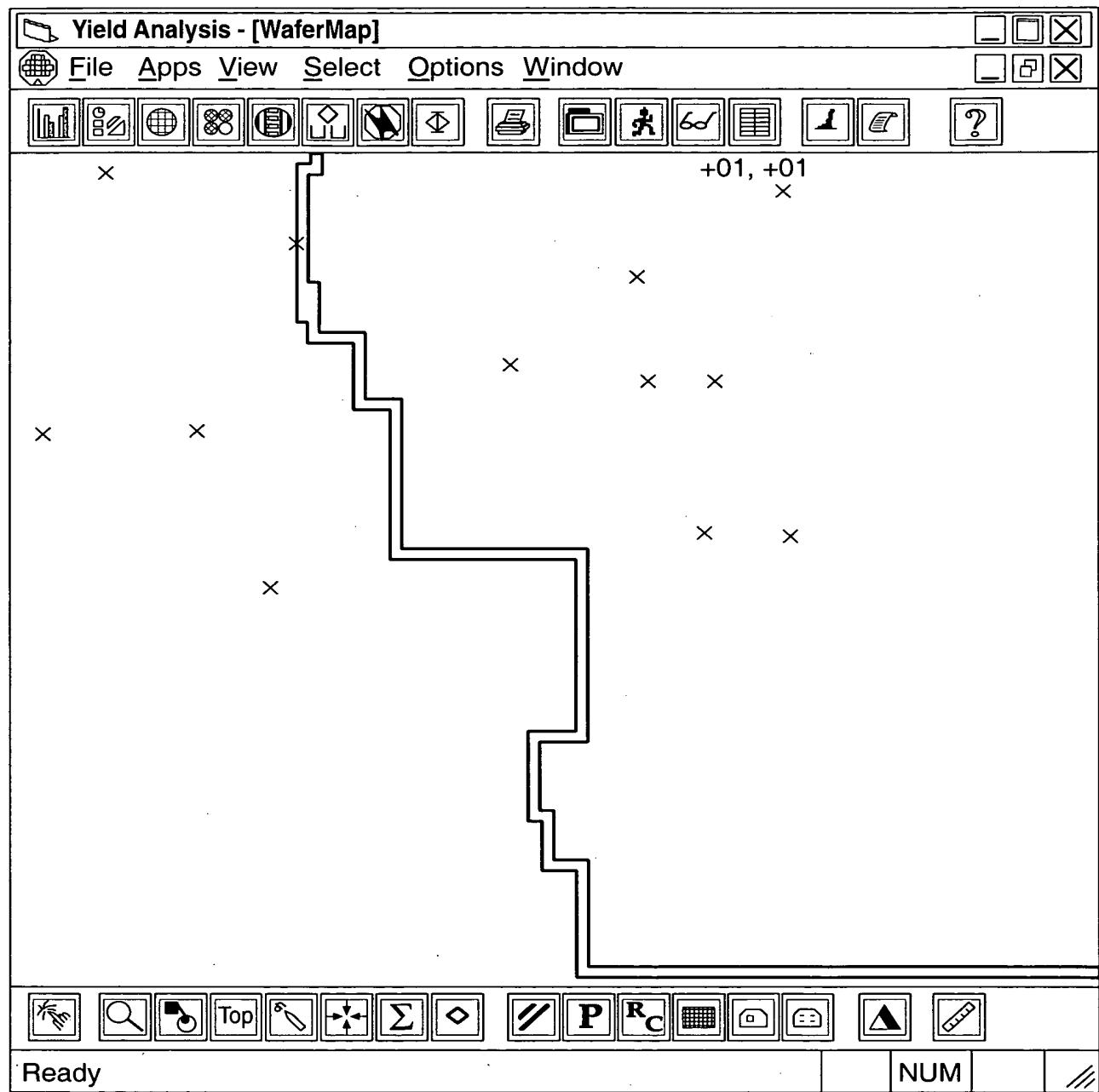


FIG.-7

APPROVED	O.G. FIG.
BY	04/28/93
DRAFTSMAN	714 784

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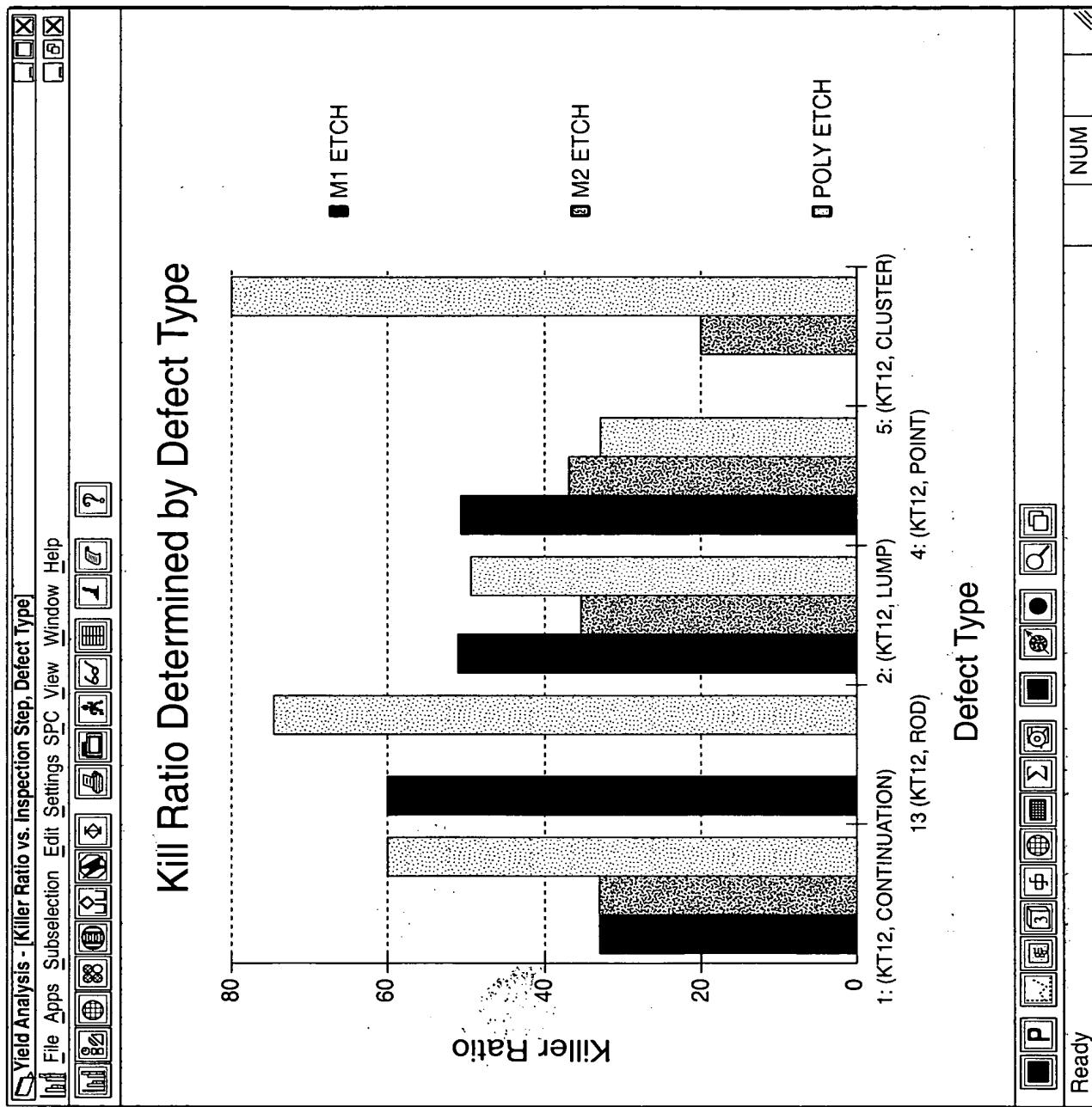


FIG.-8

APPROVED	O.G. FIG.
BY	CLASS SUBCLASS
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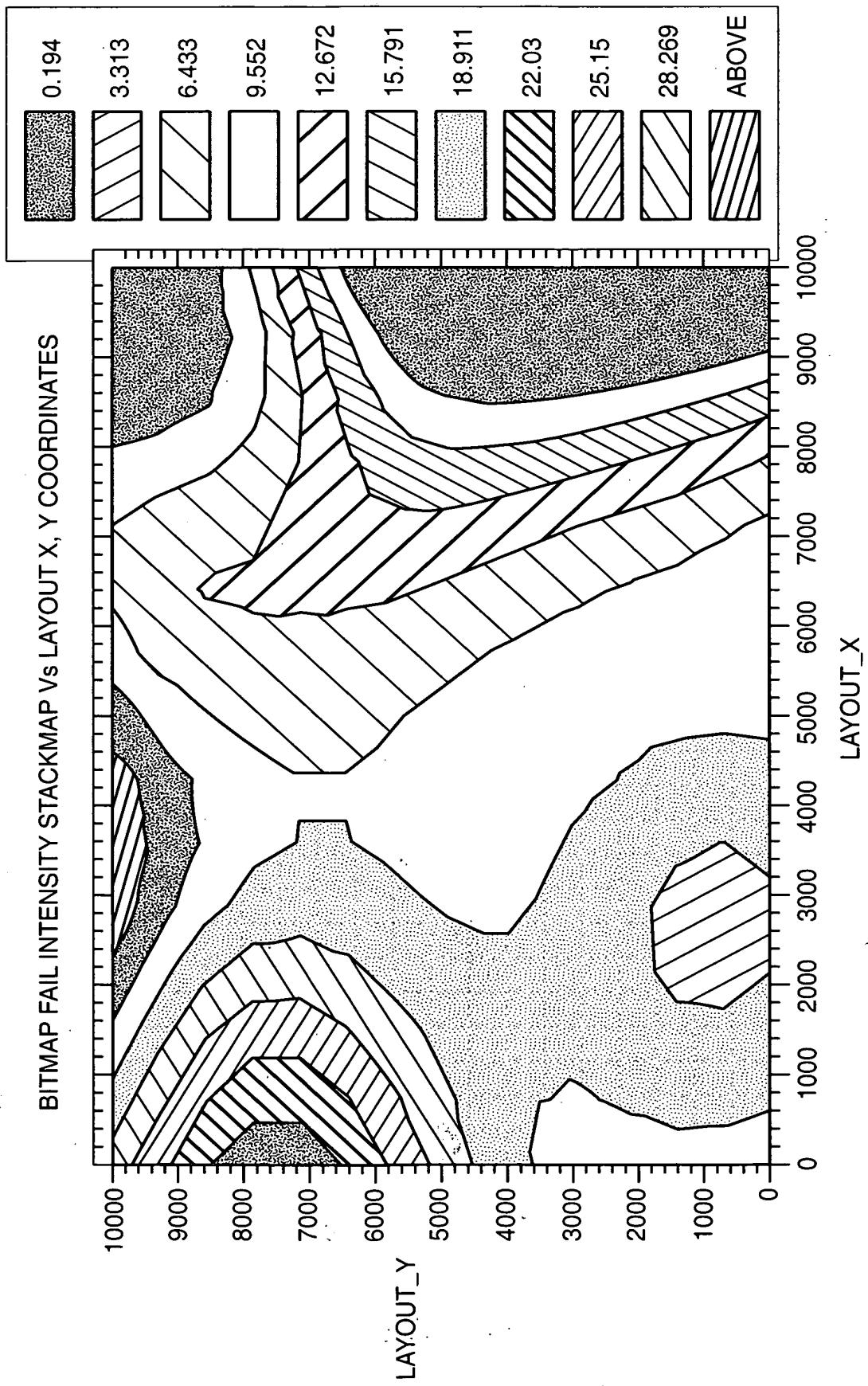


FIG._9

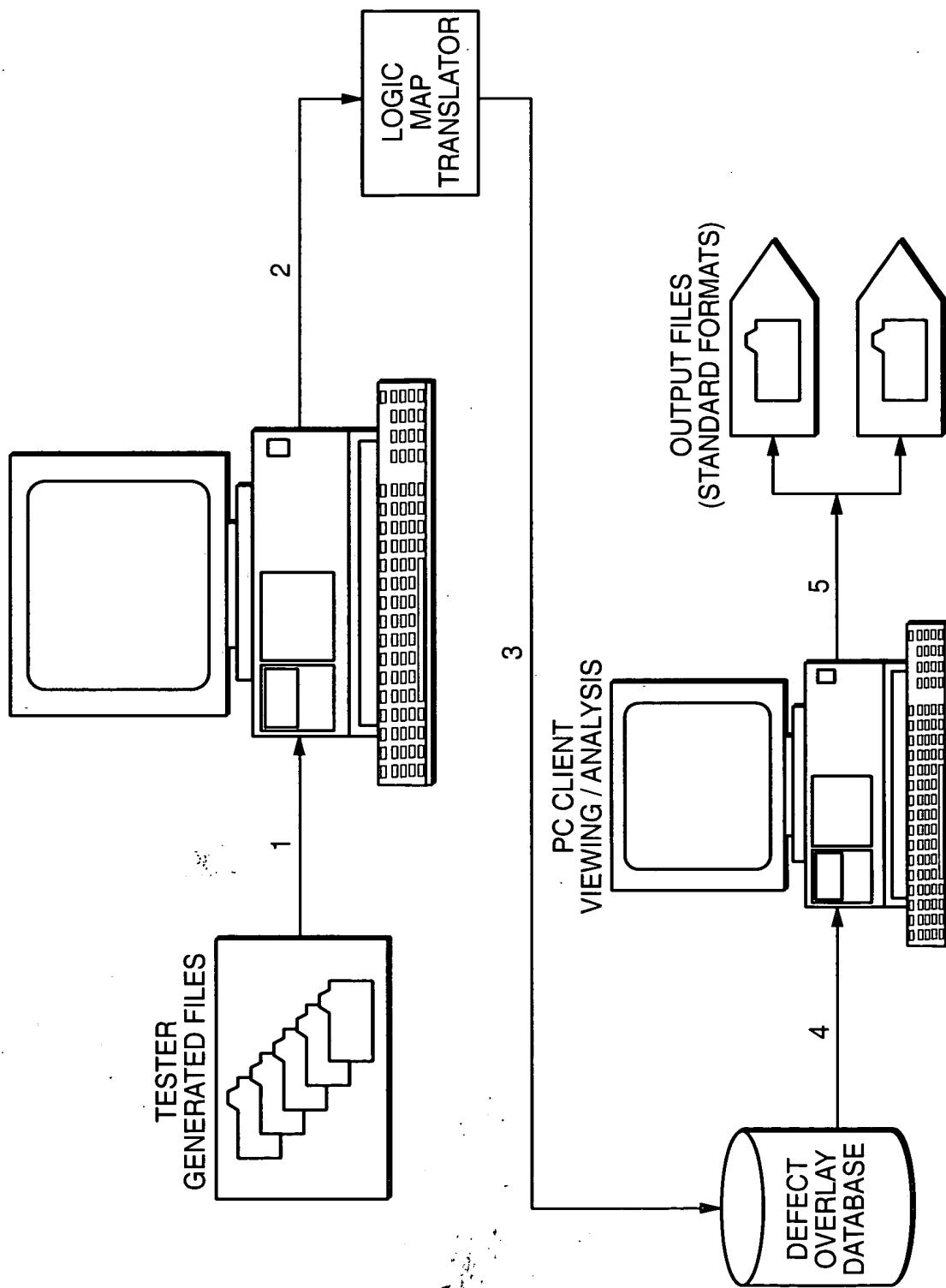


FIG._11

APPROVED	D.G. FIG.
BY	CLASS SUBCLASS
DRAFTSMAN	714 721

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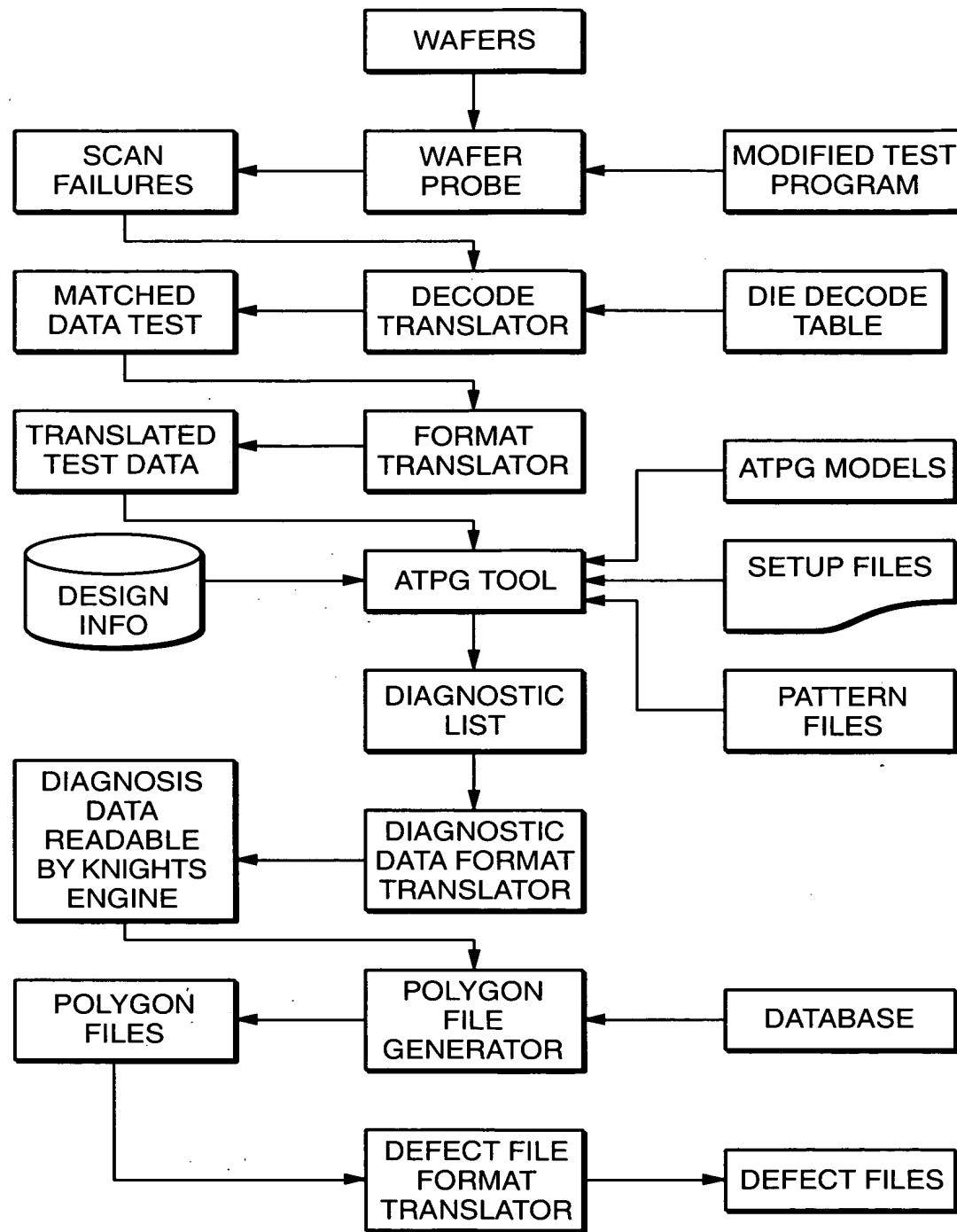


FIG._12